

BH200M Incident Light Microscope



Incident light microscope trinocular with sturdy well engineered frame and stage.

Dual Illumination with Incident and Transmitted option, available on order.

Widely used in various types of semi-conductor silicon wafer inspection, materials, science study, geology mineral analysis and precision engineering and other disciplines.

WF 10x(18) eyepieces

Plan achromatic optics and Epi Kohler illumination system and anti-reflective structure in the epi-illumination system, makes for better image clarity and contrast .

Long Working Distance Plan achromatic 5x,10x,20x,50x 100x objectives corrected for 0 cover glass

Magnification	NA	Working Distance mm
5x	0.13	15.5
10x	0.25	8.7
20x	0.40	8.8
50xS	0.60	5.1
100xS	0.80	2.0

4x and 5 position nosepiece available

Mechanical stage, with 180X145mm deck platform, moving range : 76mmX50mm

Reflected Kohler illumination, Adaptation wide voltage 90V-240V, 6V/30W halogen

bulb, brightness adjustable, with iris diaphragm and field diaphragm, the centre of field diaphragm adjustable

Accessories:

CTV mounts 1,0x & 0.5x 0.35x

Simple Polarization equipment



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